

<b>Notice of References Cited</b>	Application/Control No. 10/500,549	Applicant(s)/Patent Under Reexamination SUN, YANMENG	
	Examiner Leon-Viet Q. Nguyen	Art Unit 2611	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,285,472 A	02-1994	Leonard et al.	375/150
*	B	US-5,627,863 A	05-1997	Aslanis et al.	375/357
*	C	US-5,822,365 A	10-1998	Lee, Kyu-Don	375/150
*	D	US-6,052,408 A	04-2000	Trompower et al.	375/141
*	E	US-2001/0021199 A1	09-2001	Lee et al.	370/503
*	F	US-2001/0019578 A1	09-2001	Arima, Takenobu	375/150
*	G	US-2001/0033627 A1	10-2001	Syrjarinne, Jari	375/354
*	H	US-6,625,200 B1	09-2003	Dent, Paul W.	375/142
*	I	US-6,697,350 B2	02-2004	Lomp, Gary R.	370/342
*	J	US-2005/0220177 A1	10-2005	Lee, Jae-Yong	375/150
*	K	US-6,965,634 B1	11-2005	Clark, James M.	375/150
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.